

1                                  Supplementary Information for

2      Hydrogen absorption boosting in mildly annealed bulk

3                                   $\text{MoS}_2$

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19 I. Comparison of the valence band of an undoped and a Nb-doped  
 20 MoS<sub>2</sub> sample

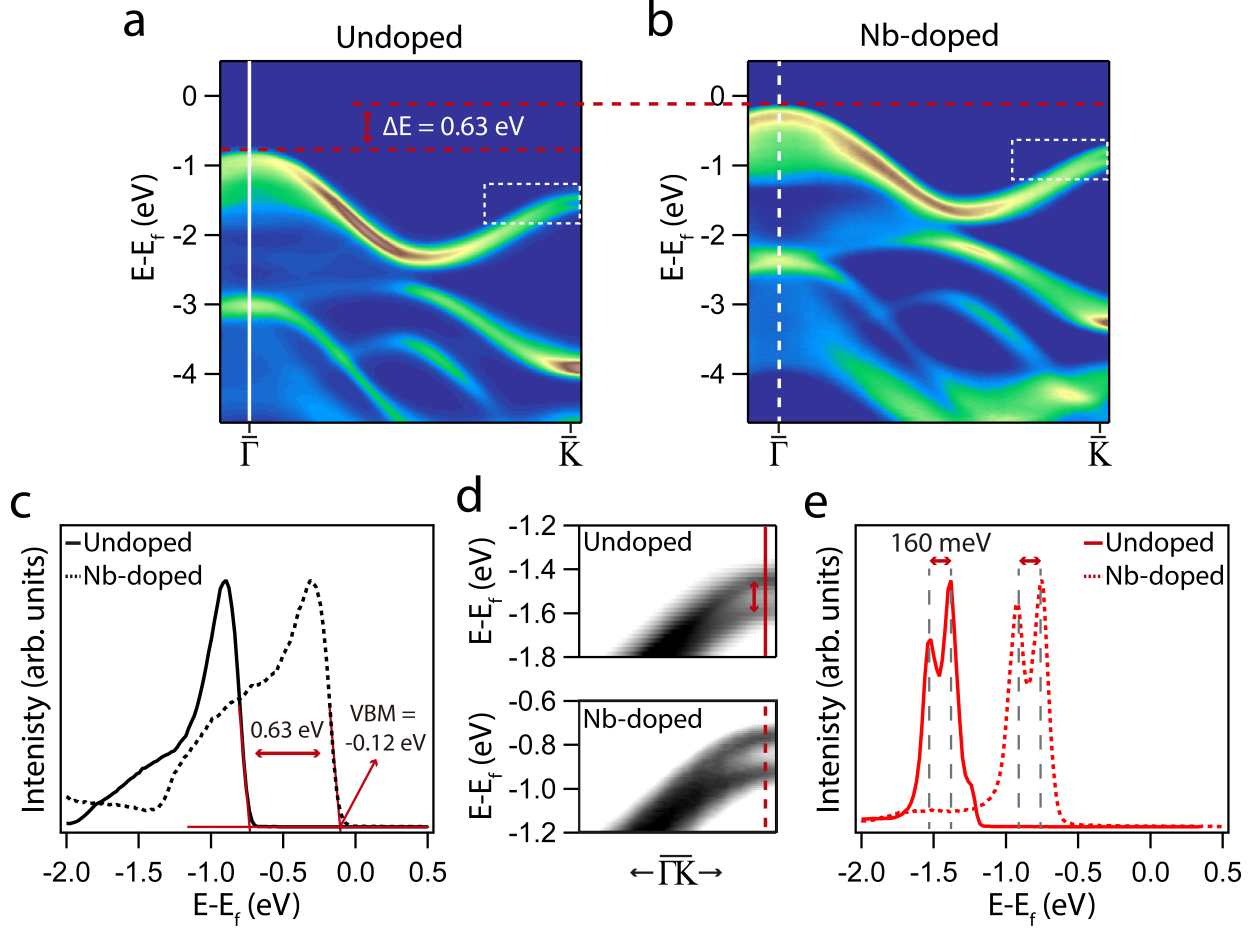


FIG. S1. (a-b) ARPES intensity showing the dispersion along the  $\bar{\Gamma}\bar{K}$  direction for the undoped and Nb-doped samples, respectively. The acceptor dopant density is  $N_a \sim 2 \cdot 10^{17} \text{ cm}^{-3}$ . (c) Energy dispersion curves (EDCs) at the  $\bar{\Gamma}$  point marked in (a-b) showing the VBM determination of the undoped (white continuous line) and Nb-doped (white dashed line) samples. A rigid band shift of 0.63 eV towards the Fermi level is obtained. The EDCs integrate a  $\Delta k_{\parallel} = 0.1 \text{ \AA}^{-1}$  region centered at  $\bar{\Gamma}$ . (d) Detail of the ARPES intensity around the  $\bar{K}$  point of the undoped (top) and Nb-doped (bottom) samples highlighting the splitting at this point. The displayed region corresponds to the white dashed boxes in panels (a-b). (e) EDCs at the  $\bar{K}$  point marked in (d) showing a spin-orbit splitting of 160 meV in the undoped (red continuous line) and Nb-doped (red dashed line) samples. The EDCs integrate a  $\Delta k_{\parallel} = 0.06 \text{ \AA}^{-1}$  region centered at  $\bar{K}$ .

## 21 II. Comparison of the core-levels of an undoped and Nb-doped MoS<sub>2</sub> 22 sample

23 In Fig. S2a-b we depict the X-ray photoemission spectroscopy (XPS) of the Mo 3*d* and  
24 S 2*p* series of core-levels (CL) for both the undoped and Nb-doped samples. Three peaks  
25 are identified after fitting the spectrum of Fig. S2a. In the undoped (Nb-doped) sample,  
26 the S 2*s* peak is observed at 226.41 eV (225.93 eV), the Mo 3*d*<sub>5/2</sub> peak at 229.21 eV (228.73  
27 eV), corresponding to Mo<sup>+4</sup> oxidation state in MoS<sub>2</sub>, and a minor peak, the Mo 3*d*<sub>3/5</sub> at  
28 232.35 eV (231.83 eV), due to Mo<sup>+6</sup> oxidation state in MoO<sub>3</sub>. The presence of MoO<sub>3</sub> can be  
29 attributed to the use of MoO<sub>3</sub> as a precursor agent during the chemical vapour transport  
30 (CVT) growth. Fig. S2b presents the S 2*p* peak and its corresponding fitting. In the  
31 undoped (Nb-doped) sample, the S 2*p*<sub>3/2</sub> component is at 162.05 eV (161.54 eV).

32 A summary of the peak shifts is presented in Fig. S2c, for the main MoS<sub>2</sub> CL peaks:  
33 0.48 eV for Mo 3*d*<sub>3/5</sub> and 0.51 eV for S 2*p*. It is important to note that no Nb 3*d* signal was  
34 detected in any of the doped sample batches employed in this work (see Fig. S2d). As said  
35 before, the Nb doping concentration is ~0.001 at.% (i.e., ~ 2 · 10<sup>17</sup> cm<sup>-3</sup>), so it is notably  
36 lower in comparison to concentrations used in other works<sup>1,2</sup>. In these studies, for a doping  
37 concentration of 0.5 at.% and higher, well-resolved Nb 3*d* CL is detected.

38 Therefore, we do not observe changes in the VB or the core-levels due to Nb doping.  
39 Both undoped and Nb-doped samples exhibit similar characteristics.

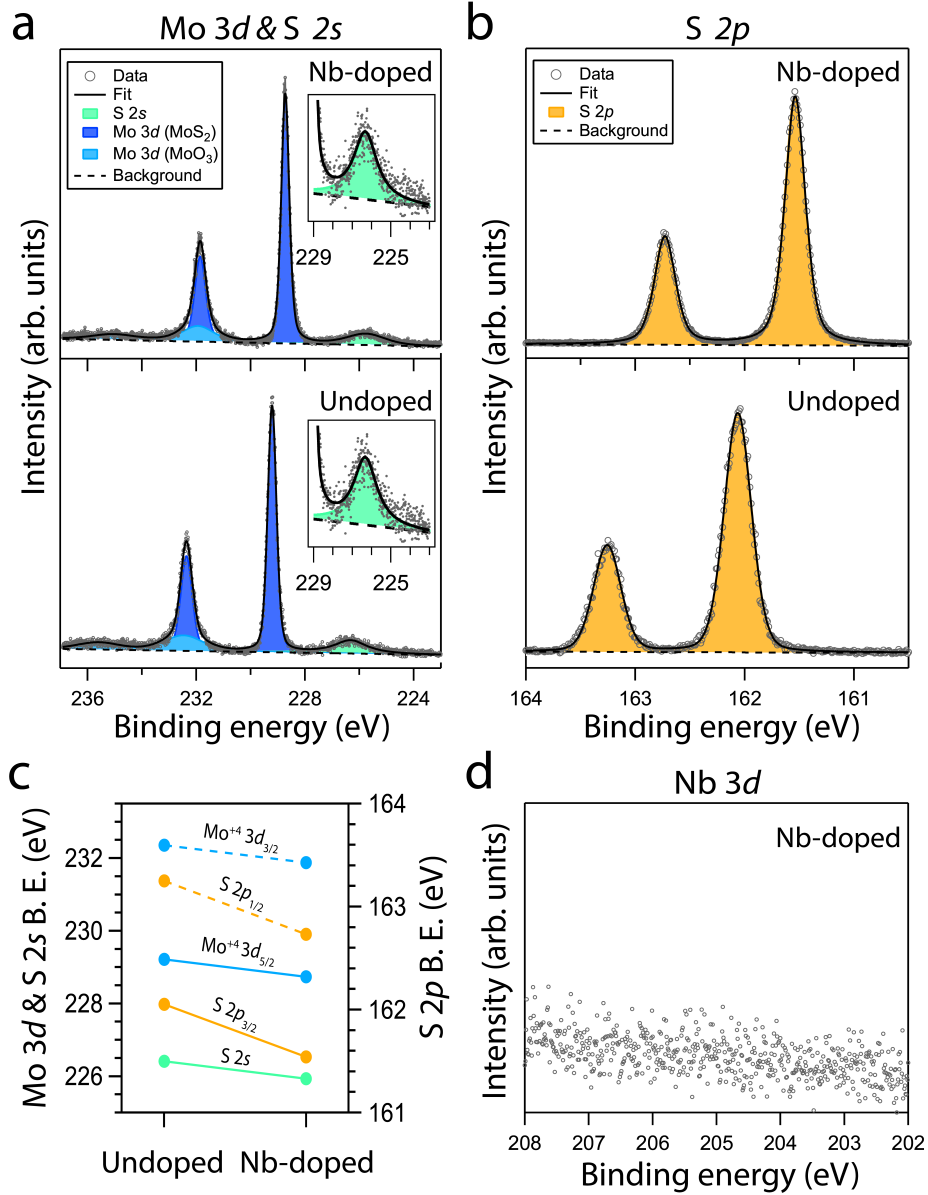


FIG. S2. XPS CLs of the undoped and undoped MoS<sub>2</sub> samples. (a) Mo 3d & S 2s. Inset: S 2s ( $h\nu = 400$  eV). (b) S 2p ( $h\nu = 200$  eV). (c) Summary of the peak shifts of the fitted components in (a-b). (d) Nb 3d ( $h\nu = 400$  eV).

40 **III. DFT band structure of a pristine single-layer of MoS<sub>2</sub> and a**  
 41 **single-layer with H atoms adsorbed in the  $V_S$**

42 In Fig. S3a-b we present the calculated band structure of the pristine MoS<sub>2</sub> structure  
 43 and the structure with two H atoms adsorbed onto the  $V_S$  (4 % of  $V_S$ ), respectively. The  
 44 calculation of panel b was performed using the unfolding package adapted to Quantum  
 45 Espresso.

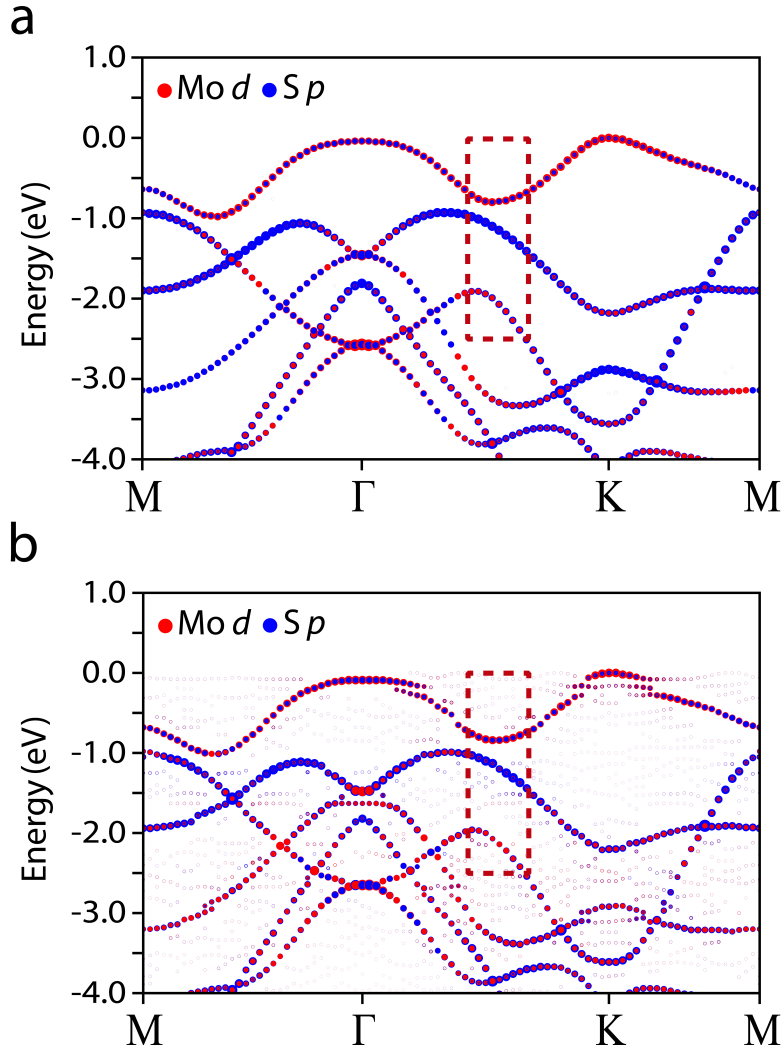


FIG. S3. (a) DFT orbital-projected electronic band structure calculated for a pristine single-layer of MoS<sub>2</sub>. (b) DFT orbital-projected electronic band structure calculated for a single-layer of MoS<sub>2</sub> with H atoms adsorbed and with 4 % of  $V_S$ . The red dashed rectangles marks the region from which the set of EDCs of Fig. 3d and Fig. 4d are taken.

46 To simulate the impact of the exposure to  $\text{H}_2$  of a surface with sulfur vacancies, various  
 47 adsorption configurations were examined. Since the evolution of the band structure after  
 48 annealing indicates that the created sulfur defect density is not very high, a 4% of  $V_S$  was  
 49 introduced accordingly. First, we observed that in the pristine scenario (no  $V_S$ ) the  $\text{H}_2$   
 50 molecule prefers to physisorb on top sites of the Mo atoms ( $T_{\text{MO}}$ ) with a vertical orienta-  
 51 tion. When  $V_S$  defects are introduced, the  $\text{H}_2$  molecule tends to occupy the  $V_S$  position.  
 52 However, the outcome depends on the molecule orientation. Vertically oriented  $\text{H}_2$  favours  
 53 physisorption, adopting an equilibrium position  $\sim 1.8 \text{ \AA}$  above the top S layer. Conversely,  
 54 when the molecule is forced to lie horizontally close to a  $V_S$ , it also dissociates. The resulting  
 55 H atoms bond to the uncoordinated Mo atoms. The dissociation scenario is 0.17 eV more  
 56 favourable than physisorption. Additional configurations were tested by placing one and  
 57 three hydrogen atoms in the  $V_S$  (not shown). These configurations are less energetically  
 58 favourable<sup>3</sup>.

#### 59 IV. Detail of the formation of a Fermi step after hydrogenation

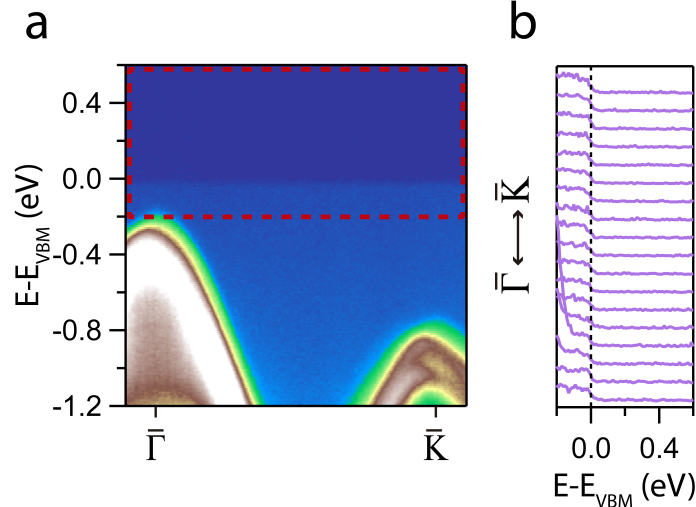


FIG. S4. (a) Enlarged region of Fig. 4a, showing details of the ARPES intensity along the  $\bar{\Gamma}\bar{K}$   
 direction for the annealed sample at 700 °C after exposure to 1000 L of  $\text{H}_2$  at a pressure of  $1 \cdot 10^{-4}$   
 mbar (“high pressure”). (b) Set of EDCs taken in the red rectangle region marked in (a). The EDCs  
 show the formation of a Fermi step after hydrogenation through the entire reciprocal space.

60 **V. Comparison between the hydrogenation at relative high and low**  
 61 **pressures**

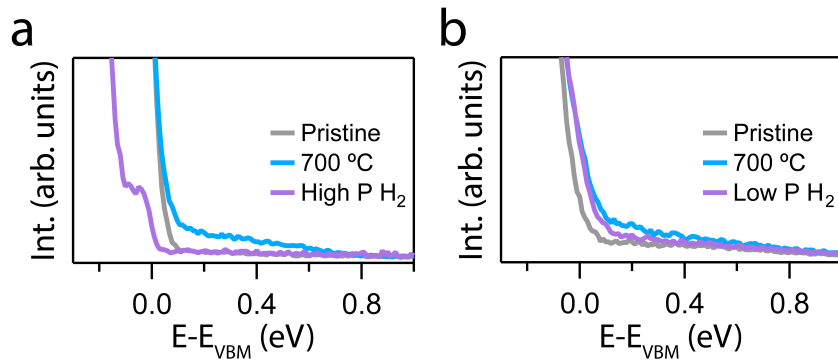


FIG. S5. Enlarged region of the EDC at  $\bar{\Gamma}$  of the sample hydrogenated after annealing at 700 °C. (a) Hydrogenation at  $1 \cdot 10^{-4}$  mbar (“high pressure” up to 1000 L and RT. (b) Hydrogenation at  $1 \cdot 10^{-6}$  mbar (“low pressure”) up to 1000 L. The pristine and 700 °C annealing EDCs are included for comparison.

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